ABSOLUTE MAXIMUM RATINGS

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(V_{AVDD} = +5V, V_{DVDD} = +3V, V_{AGND} = V_{DGND} = 0, V_{REF} = V_{REFMS} = +2.5V$ (external reference), $C_{REF} = C_{REFMS} = 0.1 \mu F, C_{REF} = 0.04 \mu F,$ $C_{REF-} = 0.1 \mu F$, $C_{REF+10-REF-} = 2.2 \mu F \parallel 0.1 \mu F$, $C_{COM} = 2.2 \mu F \parallel 0.1 \mu F$, $C_{MSV} = 2.2 \mu F \parallel 0.1 \mu F$ (unipolar devices, MAX1316/ MAX1317/MAX1318), MSV = AGND (bipolar devices, MAX1320/MAX1321/MAX1322/MAX1324/MAX1325/MAX1326), f_{CLK} = 10MHz, 50% duty cycle, INTCLK/EXTCLK = AGND (external clock), SHDN = DGND, TA = TMIN to TMAX, unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)

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ELECTRICAL CHARACTERISTICS (continued)

(VAVDD = +5V, VDVDD = +3V, VAGND = VDGND = 0, VREF = VREFMS = +2.5V (external reference), CREF = CREFMS = 0.1µF, CREF+ = CREF- = 0.1µF, CREF+-to-REF- = 2.2µF || 0.1µF, CCOM = 2.2µF || 0.1µF, CMSV = 2.2µF || 0.1µF (unipolar devices, MAX1316/ MAX1317/MAX1318), MSV = AGND (bipolar devices, MAX1320/MAX1321/MAX1322/MAX1324/MAX1325/MAX1326), f_{CLK} = 10MHz, 50% duty cycle, INTCLK/EXTCLK = AGND (external clock), SHDN = DGND, $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)

ELECTRICAL CHARACTERISTICS (continued)

(VAVDD = +5V, VDVDD = +3V, VAGND = VDGND = 0, VREF = VREFMS = +2.5V (external reference), CREF = CREFMS = 0.1µF, CREF+ = CREF- = 0.1µF, CREF+-to-REF- = 2.2µF || 0.1µF, CCOM = 2.2µF || 0.1µF, CMSV = 2.2µF || 0.1µF (unipolar devices, MAX1316/ MAX1317/MAX1318), MSV = AGND (bipolar devices, MAX1320/MAX1321/MAX1322/MAX1324/MAX1325/MAX1326), fcLK = 10MHz, 50% duty cycle, INTCLK/EXTCLK = AGND (external clock), SHDN = DGND, $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)

TIMING CHARACTERISTICS (Figures 3, 4, 5, 6 and 7) (Tables 1, 3)

Note 1: For the MAX1316/MAX1317/MAX1318, V_{IN} = 0 to +5V. For the MAX1320/MAX1321/MAX1322, V_{IN} = -5V to +5V. For the MAX1324/MAX1325/MAX1326, V_{IN} = -10V to +10V.

Note 2: All channel performance is guaranteed by correlation to a single channel test.

Note 3: Offset nulled.

Note 4: The analog input resistance is terminated to an internal bias point. Calculate the analog input current using:

$$
I_{CH_{-}} = \frac{V_{CH_{-}} - V_{BIAS}}{R_{CH_{-}}}
$$

for V_{CH} within the input voltage range.

Note 5: Throughput rate is given per channel. Throughput rate is a function of clock frequency (f_{CLK} = 10MHz). See the *Data* Throughput section for more information.

Note 6: All analog inputs are driven with an FS 100kHz sine wave.

/VI/IXI/VI

TIMING CHARACTERISTICS (Figures 3, 4, 5, 6 and 7) (Tables 1, 3) (continued)

- **Note 7:** Shutdown current is measured with analog input floating. The large amplitude of the maximum shutdown current specification is due to automatic test equipment limitations.
- **Note 8:** Defined as the change in positive full scale caused by ±5% variation in the nominal supply voltage.
- **Note 9:** CONVST must remain low for at least the acquisition period. The maximum acquisition time is limited by internal capacitor droop.
- **Note 10:** CS-to-WR and CS-to-RD pins are internally AND together. Setup and hold times do not apply.
- **Note 11:** Minimum clock frequency is limited only by the internal T/H droop rate. Limit the time between the falling edge of CONVST to the falling edge of EOLC to a maximum of 0.25ms.
- **Note 12:** To avoid T/H droop degrading the sampled analog input signals, the first clock pulse should occur within 10µs of the rising edge of CONVST, and have a minimum clock frequency of 100kHz.

Typical Operating Characteristics

 $(AV_{DD} = +5V, DV_{DD} = +3V, AGND = DGND = OV, V_{REF} = V_{REFMS} = +2.5V$ (external reference), see the Typical Operating Circuits section, f_{CLK} = 10MHz, 50% duty cycle, INTCLK/EXTCLK = AGND (external clock), SHDN = DGND, T_A = +25°C, unless otherwise noted.)

 $AV_{DD}(V)$

TEMPERATURE (°C)

TEMPERATURE (°C)

Typical Operating Characteristics (continued)

MAX1316 toc15

MAX1316 toc17b

/VI/IXI/VI

Typical Operating Characteristics (continued)

 $(AV_{DD} = +5V, DV_{DD} = +3V, AGND = DGND = 0V, V_{REF} = V_{REFMS} = +2.5V$ (external reference), see the Typical Operating Circuits section, f_{CLK} = 10MHz, 50% duty cycle, INTCLK/EXTCLK = AGND (external clock), SHDN = DGND, TA = +25°C, unless otherwise noted.)

Pin Description

Pin Description (continued)

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Pin Description (continued)

Pin Description (continued)

Figure 1. Functional Diagram

Detailed Description

The MAX1316–MAX1318/MAX1320–MAX1322/MAX1324- MAX1326 are 14-bit ADCs. They offer two, four, or eight (independently selectable) input channels, each with its own T/H circuitry. Simultaneous sampling of all active channels preserves relative phase information, making these devices ideal for motor control and power monitoring. These devices are available with 0 to +5V, ±5V, and ±10V input ranges. The 0 to +5V devices feature ±6V fault-tolerant inputs. The \pm 5V and \pm 10V devices feature ±16.5V fault-tolerant inputs. Two channels convert in 2µs; all eight channels convert in 3.8µs, with a maximum 8 channel throughput of 263ksps per channel. Internal or external reference and internal- or external-clock capability offer great flexibility and ease of use. A write-only configuration register can mask out unused channels, and a shutdown feature reduces power. A 16.6MHz, 14-bit, parallel data bus outputs the conversion result. Figure 1 shows the functional diagram of these devices.

Analog Inputs

T/H

MAX1316–MAX1318/MAX1320–MAX1322/MAX1324–MAX1326

82617431313713182222222222222222222222222224222322

To preserve phase information across these multichannel devices, each input channel has a dedicated T/H amplifier.

Use a low-input source impedance to minimize gainerror harmonic distortion. The time required for the T/H to acquire an input signal depends on the input source impedance. If the input signal's source impedance is high, the acquisition time lengthens and more time must be allowed between conversions. The acquisition time (t_1) is the maximum time the device takes to acquire the signal. Use the following formula to calculate acquisition time:

$t_1 = 10 (R_S + R_{IN}) \times 6pF$

where $R_{IN} = 2.2k\Omega$, $Rs = the input signal's source$ impedance, and t₁ is never less than 180ns. A source impedance of less than 100Ω does not significantly affect the ADC's performance.

To improve the input-signal bandwidth under AC conditions, drive the input with a wideband buffer (>50MHz) that can drive the ADC's input capacitance and settle quickly. For example, the MAX4265 can be used for +5V unipolar devices, or the MAX4350 can be used for $\pm 5V$ bipolar inputs.

The T/H aperture delay is typically 13ns. The aperturedelay mismatch between T/Hs of 50ps allows the relative phase information of up to eight different inputs to be preserved. Figure 2 shows a simplified equivalent input circuit, illustrating the ADC's sampling architecture.

Input Bandwidth

The input tracking circuitry has a 12MHz small-signal bandwidth, making it is possible to digitize high-speed transient events and measure periodic signals with bandwidths exceeding the ADC's sampling rate by using undersampling techniques. To avoid high-frequency signals being aliased into the frequency band of interest, anti-alias filtering is recommended.

Input Range and Protection

These devices provide $\pm 10V$, $\pm 5V$, or 0 to $+5V$ analog input voltage ranges. Figure 2 shows the equivalent input circuit. Overvoltage protection circuitry at the analog input provides $\pm 16.5V$ fault protection for the bipolar input devices and ±6.0V fault protection for the unipolar input devices. This fault-protection circuit limits the current going into or out of the device to less than 50mA, providing an added layer of protection from momentary overvoltage or undervoltage conditions at the analog input.

Figure 2. Typical Input Circuit

Shutdown Mode

During shutdown, the analog and digital circuits in the device power down and the device draws less than 100 μ A from AV_{DD}, and less than 100 μ A from DV_{DD}. Select shutdown mode using the SHDN input. Set SHDN high to enter shutdown mode. After coming out of shutdown, allow a 1ms wake-up time before making the first conversion. When using an external clock, apply at least 20 clock cycles with CONVST high before making the first conversion. When using internal-clock mode, wait at least 2µs before making the first conversion.

ALLON

ALLON is useful when some of the analog input channels are selected (see the Configuration Register section). Drive ALLON high to power up all input channel circuits, regardless of whether they are selected as active by the configuration register. Drive ALLON low or connect to ground to power only the input channels selected as active by the configuration register, saving 2mA per channel (typ). The wake-up time for any channel turned on with the configuration register is 2µs (typ) when ALLON is low. The wake-up time with ALLON high is only 0.01µs. New configuration-register information does not become active until the next CONVST falling edge. Therefore, when using software to control power states (ALLON = 0), pulse CONVST low once before applying the actual CONVST signal (Figure 3). With an external clock, apply at least 15 clock cycles before the second CONVST. If using internal-clock mode, wait at least 1.5µs or until the first EOC before generating the second CONVST.

Table 1. Conversion Times Using the Internal Clock

Figure 3. Software Channel Wake-Up Timing $(ALLON = 0)$

Clock Modes

These devices provide an internal clock of 10MHz (typ). Alternatively, an external clock can be used.

Internal Clock

Internal-clock mode frees the microprocessor from the burden of running the ADC conversion clock. For internalclock operation, connect INTCLK/EXTCLK to AV_{DD} and connect CLK to DGND. Table 1 illustrates the total conversion time using internal-clock mode.

External Clock For external-clock operation, connect INTCLK/EXTCLK to AGND and connect an external-clock source to CLK. Note that INTCLK/EXTCLK is referenced to the analog power supply, AV_{DD}. The external-clock frequency can be up to 15MHz, with a duty cycle between 30% and 70%. Clock frequencies of 100kHz and lower can be used, but the droop in the T/H circuits reduce linearity.

Selecting an Input Buffer

Most applications require an input buffer to achieve 14 bit accuracy. Although slew-rate and bandwidth are important, the most critical specification is settling time. The sampling requires a relatively brief sampling interval of 150ns. At the beginning of the acquisition, the internal sampling capacitor array connects to CH_ (the amplifier output), causing some output disturbance. Ensure the amplifier is capable of settling to at least 14 bit accuracy during this interval. Use a low-noise, lowdistortion, wideband amplifier (such as the MAX4350 or

MAX4265), which settles quickly and is stable with the ADC's capacitive load (in parallel with any bypass capacitors on the analog inputs).

Applications Section

Digital Interface

The bidirectional, parallel, digital interface sets the 8-bit configuration register (see the Configuration Register section) and outputs the 14-bit conversion result. The interface includes the following control signals: chip select (\overline{CS}) , read (\overline{RD}) , write (\overline{WR}) , end of conversion (EOC), end of last conversion (EOLC), convert start (CONVST), shutdown (SHDN), all on (ALLON), internalclock select (INTCLK /EXTCLK), and external-clock input (CLK). Figures 4, 5, 6, 7, Table 4, and the Timing Characteristics section show the operation of the interface. D0–D7 are bidirectional, and D8–D13 are output only. All bits are high impedance when $\overline{RD} = 1$ or $\overline{CS} = 1$.

Configuration Register

Enable channels as active by writing to the configuration register through I/O lines D0–D7 (Table 2). The bits in the configuration register map directly to the channels, with D0 controlling channel zero, and D7 controlling channel seven. Setting any bit high activates the corresponding input channel, while resetting any bit low deactivates the corresponding channel. Devices with fewer than eight channels contain some bits that have no function.

Table 2. Configuration Register

NA = Not applicable.

To write to the configuration register, pull $\overline{\text{CS}}$ and $\overline{\text{WR}}$ low, load bits D0–D7 onto the parallel bus, and force WR high. The data are latched on the rising edge of WR (Figure 4). It is possible to write to the configuration register at any point during the conversion sequence; however, it is not active until the next convert-start signal. At power-up, write to the configuration register to select the active channels before beginning a conversion. Shutdown does not change the configuration register. See the Shutdown Mode and the ALLON sections for information about using the configuration register for power saving.

Starting a Conversion

To start a conversion using internal-clock mode, pull CONVST low for at least the acquisition time (t_1) . The T/H acquires the signal while CONVST is low, and conversion begins on the rising edge of CONVST. An endof-conversion signal (\overline{EOC}) pulses low when the first result becomes available, and for each subsequent result until the end of the conversion cycle. The end-oflast-conversion signal (EOLC) goes low when the last conversion result is available (Figures 5, 6, and 7).

To start a conversion using external-clock mode, pull CONVST low for at least the acquisition time (t_1) . The T/H acquires the signal while CONVST is low, and conversion begins on the rising edge of CONVST. Apply an external clock to CLK. To avoid T/H droop degrading the sampled analog input signals, the first clock pulse should occur within 10 μ s from the rising edge of CONVST, and have a minimum clock frequency of 100kHz. The first conversion result is available for read on the rising edge of the 17th clock cycle, and subsequent conversions after every third clock cycle thereafter (Figures 5, 6, and 7).

Figure 4. Write Timing

In both internal- and external-clock modes, CONVST must be held high until the last conversion result is read. For best operation, the rising edge of CONVST must be a clean, high-speed, low-jitter digital signal.

Table 3 shows the total throughput as a function of the clock frequency and the number of channels selected for conversion. The calculations use the nominal speed of the internal clock (10MHz) and a 200ns CONVST pulse width.

Data Throughput

The data throughput (f_{TH}) of the MAX1316-MAX1318/ MAX1320–MAX1322/MAX1324–MAX1326 is a function of the clock speed (f_{CLK}). In internal-clock mode, f_{CLK} = 10MHz. In external-clock mode, 100kHz ≤ fCLK ≤ 12.5MHz. When reading during conversion (Figures 5 and 6), calculate f _H as follows:

$$
f_{TH} = \frac{1}{t_{\text{QUIET}} + \frac{16 + 3 \times (N-1) + 1}{f_{\text{CLK}}}}
$$

where N is the number of active channels and tOUIFT includes acquistion time t_{ACQ} . to unter is the period of bus inactivity before the rising edge of CONVST. Typically use t QUIET = t _{ACQ} + 50ns, and prevent disturbance on the output bus from corrupting signal acquistion. See the Starting a Conversion section for more information.

Reading a Conversion Result

Reading During a Conversion

Figures 5 and 6 show the interface signals for initiating a read operation during a conversion cycle. These figures show two channels selected for conversion. If more channels are selected, the results are available successively every third clock cycle. CS can be low at all times; it can be low during the \overline{AD} cycles, or it can be the same as \overline{RD} .

After initiating a conversion by bringing CONVST high, wait for \overline{EOC} to go low (about 1.6µs in internal-clock mode or 17 clock cycles in external-clock mode) before reading the first conversion result. Read the conversion result by bringing RD low, thus latching the data to the parallel digital-output bus. Bring RD high to release the digital bus. Wait for the next falling edge of EOC (about 300ns in internal-clock mode or three clock cycles in external-clock mode) before reading the next result. When the last result is available, EOLC goes low.

Table 3. Throughput vs. Channels Sampled (tQUIET = tACQ = 200ns, fCLK = 10MHz)

Figure 5. Read During Conversion—Two Channels Selected, Internal Clock

Figure 7. Reading After Conversion—Eight Channels Selected, External Clock

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Reading After Conversion

Figure 7 shows the interface signals for a read operation after a conversion with all eight channels enabled. At the falling edge of EOLC, on the 38th clock pulse after the initiation of a conversion, driving \overline{CS} and \overline{RD} low places the first conversion result onto the parallel bus, which can be latched on the rising edge of RD. Successive low pulses of RD place the successive conversion results onto the bus. Pulse CONVST low to initiate a new conversion.

Power-Up Reset

At power-up, all channels are selected for conversion (see the Configuration Register section). After applying power, allow a 1.0ms wake-up time to elapse before initiating the first conversion. Then, hold CONVST high for at least 2.0µs after the wake-up time is complete. If using an external clock, apply 20 clock pulses to CLK with CONVST high before initiating the first conversion.

Reference

Internal Reference

The internal-reference circuits provide for analog input voltages of 0 to +5V unipolar (MAX1316/MAX1317/ MAX1318), ±5V bipolar (MAX1320/MAX1321/MAX1322), or ±10V bipolar (MAX1324/MAX1325/MAX1326). Install external capacitors for reference stability, as indicated in Table 4, and as shown in the Typical Operating Circuits.

External Reference

Connect a +2.0V to +3.0V external reference at REFMS and/or REF. When connecting an external reference, the input impedance is typically 5kΩ. The external reference must be able to drive 200µA of current and have a low output impedance. For more information about using external references see the Transfer Functions section.

Layout, Grounding, and Bypassing

For best performance use PC boards with ground planes. Board layout should ensure that digital and analog signal lines are separated from each other. Do not run analog and digital lines parallel to one another (especially clock lines), or do not run digital lines underneath the ADC package. Figure 8 shows the recommended system ground connections when not using a ground plane. A single-point analog ground (star ground point) should be established at AGND, separate from the logic ground. All other analog grounds and DGND should be connected to this ground.

Figure 8. Power-Supply Grounding and Bypassing

Table 4. Reference Bypass Capacitors

NA = Not applicable (connect MSV directly to AGND).

No other digital system ground should be connected to this single-point analog ground. The ground return to the power supply for this ground should be low impedance and as short as possible for noise-free operation. High-frequency noise in the V_{DD} power supply may affect the high-speed comparator in the ADC. Bypass these supplies to the single-point analog ground with 0.1µF and 2.2µF bypass capacitors close to the device. If the +5V power supply is very noisy, a ferrite bead can be connected as a lowpass filter, as shown in Figure 8.

Transfer Functions

Bipolar ±10V Devices

Table 5 and Figure 9 show the two's complement transfer function for the MAX1324/MAX1325/MAX1326 with a ±10V input range. The full-scale input range (FSR) is eight times the voltage at REF. The internal +2.500V reference gives a +20V FSR, while an external +2V to +3V reference allows an FSR of +16V to +24V, respectively. Calculate the LSB size using the following equation:

$$
LSB = \frac{8 \times V_{REF}}{2^{14}}
$$

This equals 1.2207mV with a +2.5V internal reference.

The input range is centered about V_{MSV}. Normally, MSV = AGND, and the input is symmetrical about zero. For a custom midscale voltage, drive MSV with an external voltage source. Noise present on MSV directly couples into the ADC result. Use a precision, low-drift voltage reference with adequate bypassing to prevent MSV from degrading ADC performance. For maximum FSR, be careful not to violate the absolute maximum voltage ratings of the analog inputs when choosing V_{MSV}.

Determine the input voltage as a function of VREF, VMSV, and the output code in decimal using the following equation:

$$
V_{CH_{-}} = LSB \times CODE_{10} + V_{MSV}
$$

Bipolar ±5V Devices

Table 6 and Figure 10 show the two's complement transfer function for the MAX1320/MAX1321/MAX1322 with a ±5V input range. The FSR is four times the voltage at REF. The internal +2.500V reference gives a +10V FSR, while an external +2V to +3V reference allows an FSR of +8V to +12V, respectively. Calculate the LSB size using the following equation:

$$
LSB = \frac{4 \times V_{REF}}{2^{14}}
$$

This equals 0.6104mV when using the internal reference.

Table 5. ±10V Bipolar Code Table

Figure 9. ±10V Bipolar Transfer Function

Figure 10. ±5V Bipolar Transfer Function

The input range is centered about V_{MSV}. Normally, MSV = AGND, and the input is symmetrical about zero. For a custom midscale voltage, drive MSV with an external voltage source. Noise present on MSV directly couples into the ADC result. Use a precision, low-drift voltage reference with adequate bypassing to prevent MSV from degrading ADC performance. For maximum FSR, be careful not to violate the absolute maximum voltage ratings of the analog inputs when choosing VMSV. Determine the input voltage as a function of VREF, VMSV, and the output code in decimal using the following equation:

$$
V_{CH_{-}} = LSB \times CODE_{10} + V_{MSV}
$$

Unipolar 0 to +5V Devices

Table 7 and Figure 11 show the offset binary transfer function for the MAX1316/MAX1317/MAX1318 with a 0 to +5V input range. The FSR is two times the voltage at REF. The internal +2.500V reference gives a +5V FSR, while an external +2V to +3V reference allows an FSR of +4V to +6V, respectively. Calculate the LSB size using the following equation:

$$
LSB = \frac{2 \times V_{REF}}{2^{14}}
$$

This equals 0.3052mV when using the internal reference.

Table 6. ±5V Bipolar Code Table

Table 7. 0 to +5V Unipolar Code Table

Figure 11. 0 to +5V Unipolar Transfer Function

The input range is centered about V_{MSV}, which is internally set to +2.500V. For a custom midscale voltage, drive REFMS with an external voltage source and MSV will follow REF_{MS}. Noise present on MSV or REF_{MS} directly couples into the ADC result. Use a precision, low-drift voltage reference with adequate bypassing to prevent MSV from degrading ADC performance. For maximum FSR, be careful not to violate the absolute maximum voltage ratings of the analog inputs when choosing VMSV. Determine the input voltage as a function of VREF, VMSV, and the output code in decimal using the following equation:

$$
V_{CH_{-}} = LSB \times CODE_{10} + (V_{MSV} - 2.500V)
$$

Definitions

Integral Nonlinearity

Integral nonlinearity (INL) is the deviation of the values on an actual transfer function from a straight line. For these devices, this straight line is a line drawn between the end points of the transfer function, once offset and gain errors have been nullified.

Differential Nonlinearity

Differential nonlinearity (DNL) is the difference between an actual step width and the ideal value of 1 LSB. For these devices, the DNL of each digital output code is measured and the worst-case value is reported in the Electrical Characteristics table. A DNL error specification of less than \pm 1 LSB quarantees no missing codes and a monotonic transfer function.

Unipolar Offset Error

For the unipolar MAX1316/MAX1317/MAX1318, the ideal zero-scale transition from 0x0000 to 0x0001 occurs at 1 LSB (see Figure 11). The unipolar offset error is the amount of deviation between the measured zero-scale transition point and the ideal zero-scale transition point.

Bipolar Offset Error

For the bipolar MAX1320/MAX1321/MAX1322/ MAX1324/MAX1325/MAX1326, the ideal zero-point transition from 0x3FFF to 0x0000 occurs at MSV, which is usually connected to ground (see Figures 9 and 10). The bipolar offset error is the amount of deviation between the measured zero-point transition and the ideal zero-point transition.

Gain Error

The ideal full-scale transition from 0x1FFE to 0x1FFF occurs at 1 LSB below full scale (see the Transfer Functions section). The gain error is the amount of deviation between the measured full-scale transition point and the ideal full-scale transition point, once offset error has been nullified.

Signal-to-Noise Ratio

For a waveform perfectly reconstructed from digital samples, signal-to-noise ratio (SNR) is the ratio of the full-scale analog input (RMS value) to the RMS quantization error (residual error). The ideal, theoretical minimum analog-to-digital noise is caused by quantization noise error only and results directly from the ADC's resolution (N bits):

$$
SNR = (6.02 \times N + 1.76)dB
$$

where $N = 14$ bits.

In reality, there are other noise sources besides quantization noise: thermal noise, reference noise, clock jitter, etc. SNR is computed by taking the ratio of the RMS signal to the RMS noise, which includes all spectral components minus the fundamental, the first five harmonics, and the DC offset.

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Signal-to-Noise Plus Distortion

Signal-to-noise plus distortion (SINAD) is the ratio of the fundamental input frequency's RMS amplitude to the RMS equivalent of all the other ADC output signals:

$$
SINAD(dB) = 20 \times log \left[\frac{Signal_{RMS}}{(Noise + Distortion)_{RMS}} \right]
$$

Effective Number of Bits

The effective number of bits (ENOB) indicates the global accuracy of an ADC at a specific input frequency and sampling rate. An ideal ADC's error consists of quantization noise only. With an input range equal to the fullscale range of the ADC, calculate the ENOB as follows:

$$
ENOB = \frac{SINAD - 1.76}{6.02}
$$

Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the RMS sum of the first five harmonics of the input signal to the fundamental itself. This is expressed as:

$$
\text{THD} = 20 \times \log \left[\frac{\sqrt{{v_2}^2 + {v_3}^2 + {v_4}^2 + {v_5}^2}}{v_1} \right]
$$

where V_1 is the fundamental amplitude and V_2 through V₅ are the 2nd-through 5th-order harmonics.

Spurious-Free Dynamic Range

Spurious-free dynamic range (SFDR) is the ratio of the RMS amplitude of the fundamental (maximum signal component) to the RMS value of the next-largest frequency component.

Aperture Delay

Aperture delay (tAD) is the time delay from the sampling clock edge to the instant when an actual sample is taken.

Aperture Jitter

Aperture Jitter (tAJ) is the sample-to-sample variation in aperture delay.

Channel-to-Channel Isolation

Channel-to-channel isolation indicates how well each analog input is isolated from the other channels. Channelto-channel isolation is measured by applying DC to channels 1 to 7, while a -0.5dBFS sine wave is applied to channel 0. A 100kHz FFT is taken for channel 0 and channel 1. Channel-to-channel isolation is expressed in dB as the power ratio of the two 100kHz magnitudes.

Small-Signal Bandwidth

A small -20dBFS analog input signal is applied to an ADC in a manner that ensures that the signal's slew rate does not limit the ADC's performance. The input frequency is then swept up to the point where the amplitude of the digitized conversion result has decreased 3dB.

Full-Power Bandwidth

A large -0.5dBFS analog input signal is applied to an ADC, and the input frequency is swept up to the point where the amplitude of the digitized conversion result has decreased by 3dB. This point is defined as fullpower input bandwidth frequency.

Chip Information

TRANSISTOR COUNT: 80,000 PROCESS: BiCMOS 0.6µm

Typical Operating Circuits

MAXIM

Typical Operating Circuits (continued)

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MAX1316–MAX1318/MAX1320–MAX1322/MAX1324–MAX1326

Package Information

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For the latest package outline information and land patterns, go to **www.maxim-ic.com/packages**.

Revision History

Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.

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